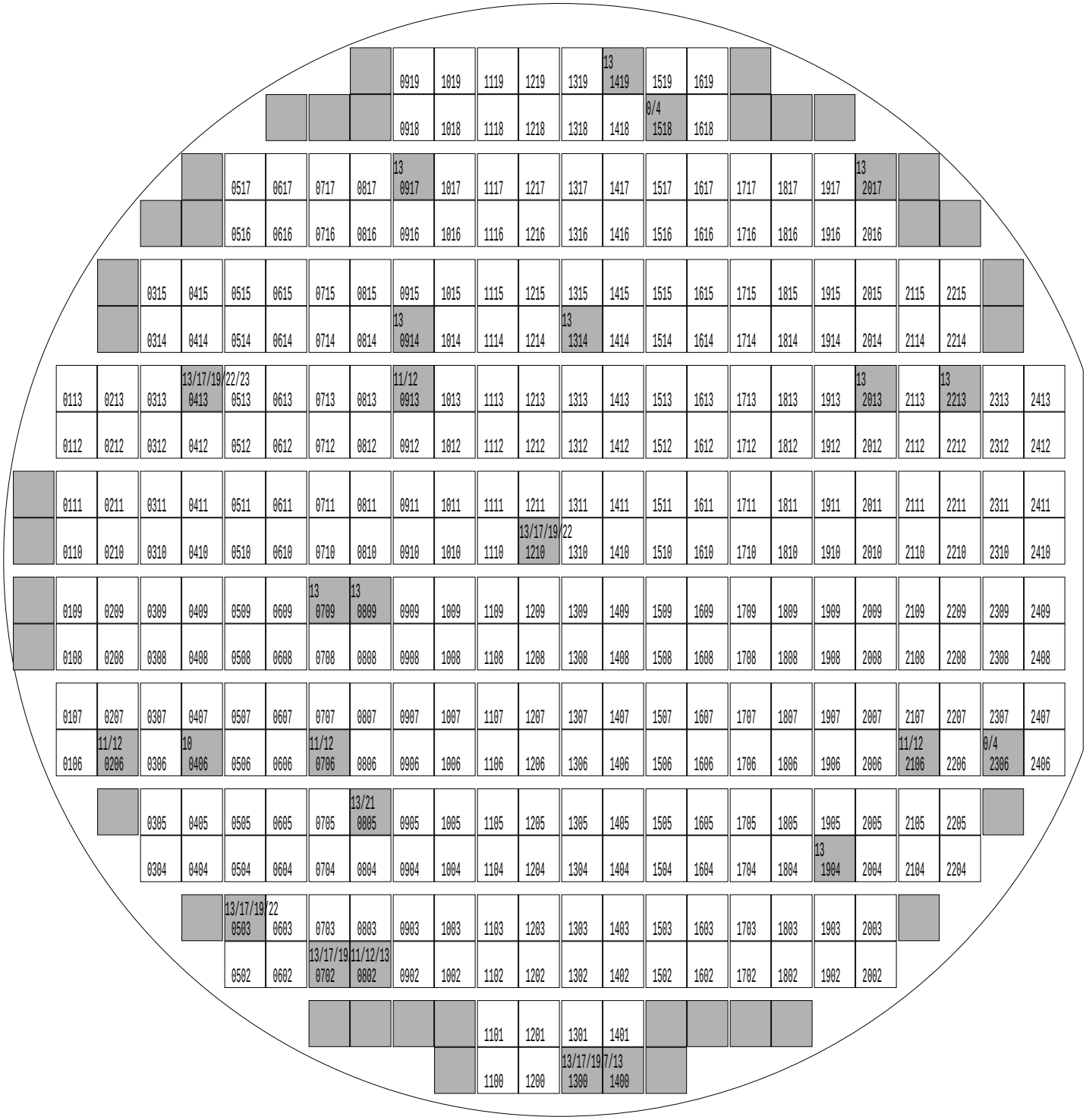
Wafer Map: KYMG51T



Date probed:	Mon 01 Mar 2004
Chips passed:	335/360
Yield:	93%
Digital failures:	2
Power supply failures:	1
Channel defects (Peds & Cal):	12
Pipeline defects:	18